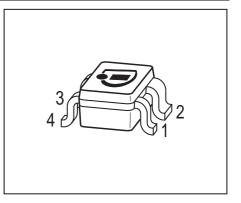


BFP405

NPN Silicon RF Transistor

- For low current applications
- For oscillators up to 12 GHz
- Noise figure F = 1.25 dB at 1.8 GHz outstanding $G_{ms} = 23$ dB at 1.8 GHz
- Transition frequency $f_{\rm T}$ = 25 GHz
- Gold metallization for high reliability
- SIEGET ® 25 GHz fT Line



ESD (Electrostatic discharge) sensitive device, observe handling precaution!

Туре	Marking	Pin Configuration					Package	
BFP405	ALs	1=B	2=E	3=C	4=E	-	-	SOT343

Maximum Ratings				
Parameter	Symbol	Value	Unit	
Collector-emitter voltage	V _{CEO}		V	
$T_{A} > 0 \ ^{\circ}C$		4.5		
$T_{A} \leq 0 \ ^{\circ}C$		4.1		
Collector-emitter voltage	V _{CES}	15		
Collector-base voltage	V _{CBO}	15		
Emitter-base voltage	V _{EBO}	1.5		
Collector current	I _C	12	mA	
Base current	I _B	1		
Total power dissipation ¹⁾	P _{tot}	55	mW	
<i>T</i> _S ≤ 120 °C				
Junction temperature	Ti	150	°C	
Ambient temperature	T _A	-65 150		
Storage temperature	T _{stg}	-65 150		
Thermal Resistance				
Parameter	Symbol	Value	Unit	
Junction - soldering point ²⁾	R _{thJS}	≤ 520	K/W	

 $^{1}T_{S}$ is measured on the collector lead at the soldering point to the pcb

 $^2 \rm For}$ calculation of ${\it R}_{\rm thJA}$ please refer to Application Note Thermal Resistance



Parameter	Symbol	Values			Unit
		min.	typ.	max.]
DC Characteristics					
Collector-emitter breakdown voltage	V _{(BR)CEO}	4.5	5	-	V
$I_{\rm C} = 1 {\rm mA}, I_{\rm B} = 0$					
Collector-emitter cutoff current	I _{CES}	-	-	10	μA
$V_{\rm CE} = 15 \text{ V}, \ V_{\rm BE} = 0$					
Collector-base cutoff current	I _{CBO}	-	-	100	nA
$V_{\rm CB} = 5 \text{V}, I_{\rm E} = 0$					
Emitter-base cutoff current	I _{EBO}	-	-	1	μA
$V_{\rm EB} = 0.5 \text{V}, I_{\rm C} = 0$					
DC current gain	h _{FE}	60	95	130	-
$I_{\rm C}$ = 5 mA, $V_{\rm CE}$ = 4 V, pulse measured					

Electrical Characteristics at $T_A = 25^{\circ}$ C, unless otherwise specified



Parameter	Symbol		Unit		
		min.	typ.	max.	
AC Characteristics (verified by random samplin	g)				
Transition frequency	f _T	18	25	-	GHz
$I_{\rm C}$ = 10 mA, $V_{\rm CE}$ = 3 V, f = 2 GHz					
Collector-base capacitance	C _{cb}	-	0.05	0.1	pF
$V_{\rm CB} = 2 {\rm V}, f = 1 {\rm MHz}, V_{\rm BE} = 0 ,$					
emitter grounded					
Collector emitter capacitance	C _{ce}	-	0.24	-]
$V_{CE} = 2 V, f = 1 MHz, V_{BE} = 0$,					
base grounded					
Emitter-base capacitance	C _{eb}	-	0.29	-]
$V_{\rm EB} = 0.5 \text{ V}, f = 1 \text{ MHz}, V_{\rm CB} = 0$,					
collector grounded					
Noise figure	F	-	1.25	-	dB
$I_{\rm C}$ = 2 mA, $V_{\rm CE}$ = 2 V, f = 1.8 GHz, $Z_{\rm S}$ = $Z_{\rm Sopt}$					
Power gain, maximum stable ¹⁾	G _{ms}	-	23	-	dB
$I_{\rm C} = 5 \text{ mA}, V_{\rm CE} = 2 \text{ V}, Z_{\rm S} = Z_{\rm Sopt},$					
$Z_{\rm L} = Z_{\rm Lopt}$, $f = 1.8 {\rm GHz}$					
Insertion power gain	S ₂₁ ²	14	18.5	-	
V _{CE} = 2 V, <i>I</i> _C = 5 mA, <i>f</i> = 1.8 GHz,					
$Z_{\rm S} = Z_{\rm L} = 50 \ \Omega$					
Third order intercept point at output ²⁾	IP ₃	-	15	-	dBm
V _{CE} = 2 V, <i>I</i> _C = 5 mA, <i>f</i> = 1.8 GHz,					
$Z_{\rm S} = Z_{\rm L} = 50 \ \Omega$					
1dB Compression point at output	P _{-1dB}	-	5	-]
$I_{\rm C} = 5 \text{ mA}, V_{\rm CE} = 2 \text{ V}, Z_{\rm S} = Z_{\rm L} = 50 \Omega,$					
f = 1.8 GHz					

Electrical Characteristics at $T_A = 25^{\circ}$ C, unless otherwise specified

 ${}^{1}G_{\rm ms} = |S_{21} / S_{12}|$

 2 IP3 value depends on termination of all intermodulation frequency components. Termination used for this measurement is 50 Ω from 0.1 MHz to 6 GHz



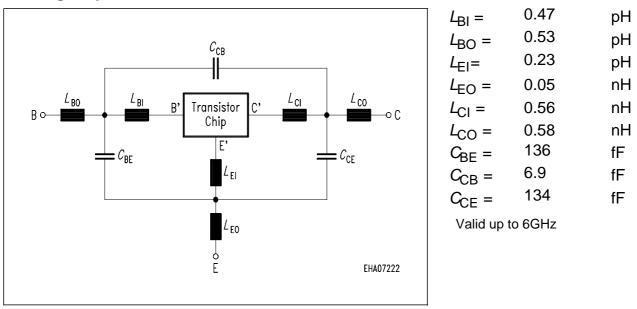
SPICE Parameter (Gummel-Poon Model, Berkley-SPICE 2G.6 Syntax):

Transito	r Chip Data	:						
IS =	0.21024	fA	BF =	83.23	-	NF =	1.0405	-
VAF =	39.251	V	IKF =	0.16493	А	ISE =	15.761	fA
NE =	1.7763	-	BR =	10.526	-	NR =	0.96647	-
VAR =	34.368	V	IKR =	0.25052	mA	ISC =	0.037223	fA
NC =	1.3152	-	RB =	15	Ω	IRB =	0.21215	mΑ
RBM =	1.3491	Ω	RE =	1.9289	-	RC =	0.12691	Ω
CJE =	3.7265	fF	VJE =	0.70367	V	MJE =	0.37747	-
TF =	4.5899	ps	XTF =	0.3641	-	VTF =	0.19762	V
ITF =	1.3364	А	PTF =	0	deg	CJC =	96.941	fF
VJC =	0.99532	V	MJC =	0.48652	-	XCJC =	0.08161	-
TR =	1.4935	ns	CJS =	0	fF	VJS =	0.75	V
MJS =	0	-	XTB =	0	-	EG =	1.11	eV
XTI =	3	-	FC =	0.99469		TNOM	300	K

C`-E`-dioden Data (Berkley-Spice 1G.6 Syntax): IS = 2 fA; N = 1.02 -, $RS = 20 \Omega$

All parameters are ready to use, no scalling is necessary.

Package Equivalent Circuit:



The SOT343 package has two emitter leads. To avoid high complexity to the package equivalent circuit both leads are combined in one electrical connection

Extracted on behalf of Infineon Technologies AG by: Institut für Mobil- und Satellitentechnik (IMST)

For examples and ready to use parameters please contact your local Infineon Technologies distributor or sales office to obtain a InfineonTechnologies CD-ROM or see Internet: http://www.infineon.com/silicondiscretes

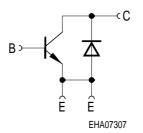


For non-linear simulation:

- Use transistor chip parameters in Berkeley SPICE 2G.6 syntax for all simulators.
- If you need simulation of the reverse characteristics, add the diode with the C'-E'- diode data between collector and emitter.
- Simulation of package is not necessary for frequencies < 100MHz.
 For higher frequencies add the wiring of package equivalent circuit around the non-linear transistor and diode model.

Note:

• This transistor is constructed in a common emitter configuration. This feature causes an additional reverse biased diode between emitter and collector, which does not effect normal operation.



Transistor Schematic Diagram

The common emitter configuration shows the following advantages:

- Higher gain because of lower emitter inductance.
- Power is dissipated via the grounded emitter leads, because the chip is mounted on copper emitter leadframe.

Please note, that the broadest lead is the emitter lead.

Common Emitter S- and Noise-parameter

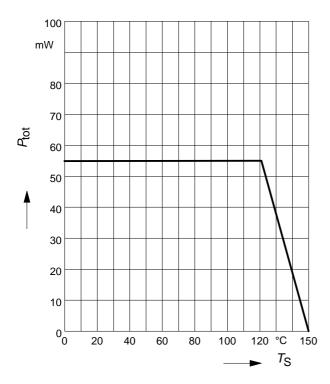
For detailed S- and Noise-parameters please contact your local Infineon Technologies distributor or sales office to obtain a Infineon Technologies Application Notes CD-ROM or see Internet: http://www.infineon.com/silicondiscretes



BFP405

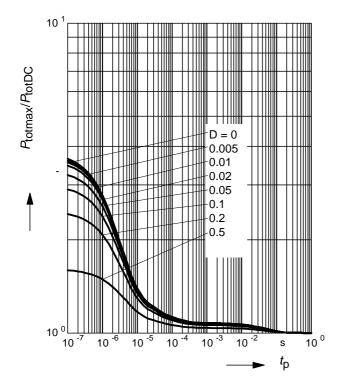
Total power dissipation $P_{tot} = f(T_S)$

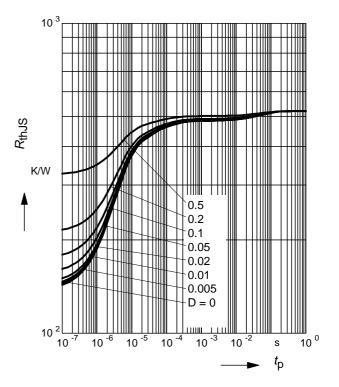
Permissible Pulse Load $R_{\text{thJS}} = f(t_{\text{p}})$



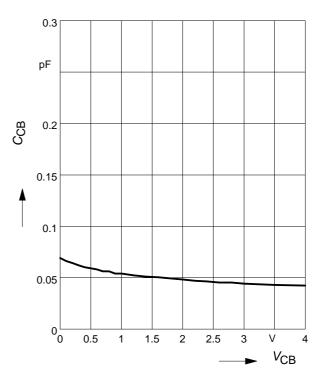
Permissible Pulse Load

 $P_{\text{totmax}}/P_{\text{totDC}} = f(t_{p})$





Collector-base capacitance $C_{cb}=f(V_{CB})$ f = 1MHz



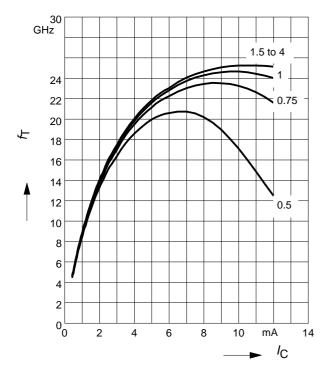


BFP405

Transition frequency $f_{T} = f(I_{C})$

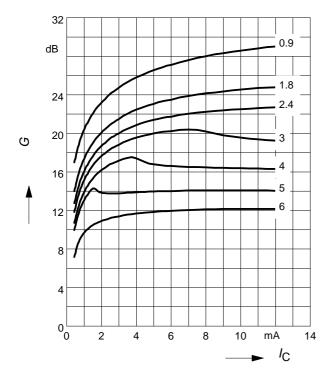
f = 2 GHz

 V_{CE} = parameter in V

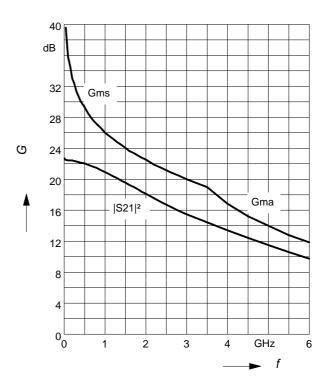


Power gain
$$G_{ma}$$
, $G_{ms} = f(I_C)$
 $V_{CE} = 2V$

f = parameter in GHz

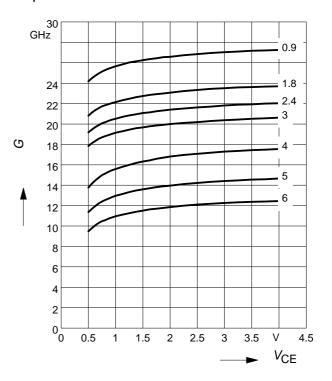


Power gain G_{ma} , G_{ms} , $|S_{21}|^2 = f(t)$ $V_{CE} = 2 \text{ V}$, $I_C = 5 \text{ mA}$



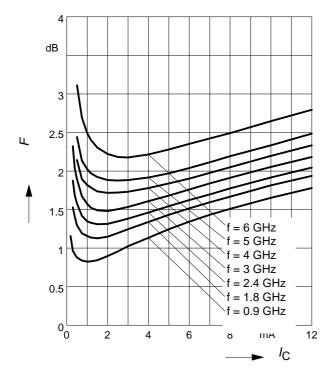
Power gain G_{ma} , $G_{ms} = f (V_{CE})$ $I_{C} = 5 \text{ mA}$

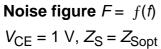
f = parameter in GHz

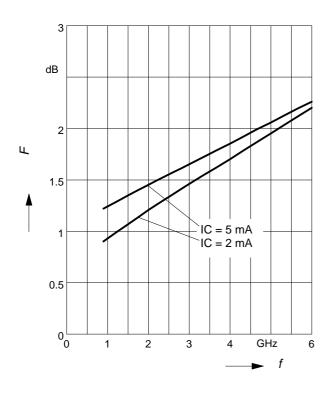




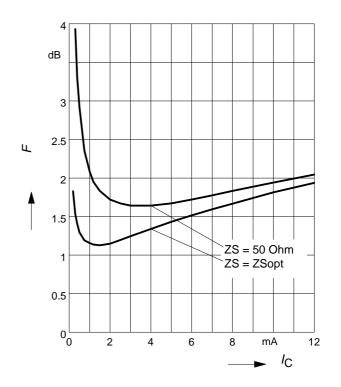
Noise figure $F = f(I_C)$ $V_{CE} = 2 \text{ V}, Z_S = Z_{Sopt}$





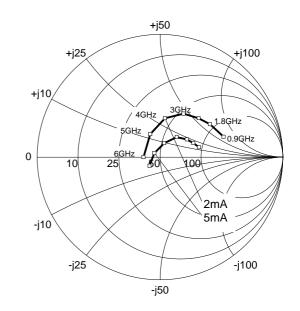


Noise figure $F = f(I_C)$ $V_{CE} = 2 \text{ V}, f = 1.8 \text{ GHz}$

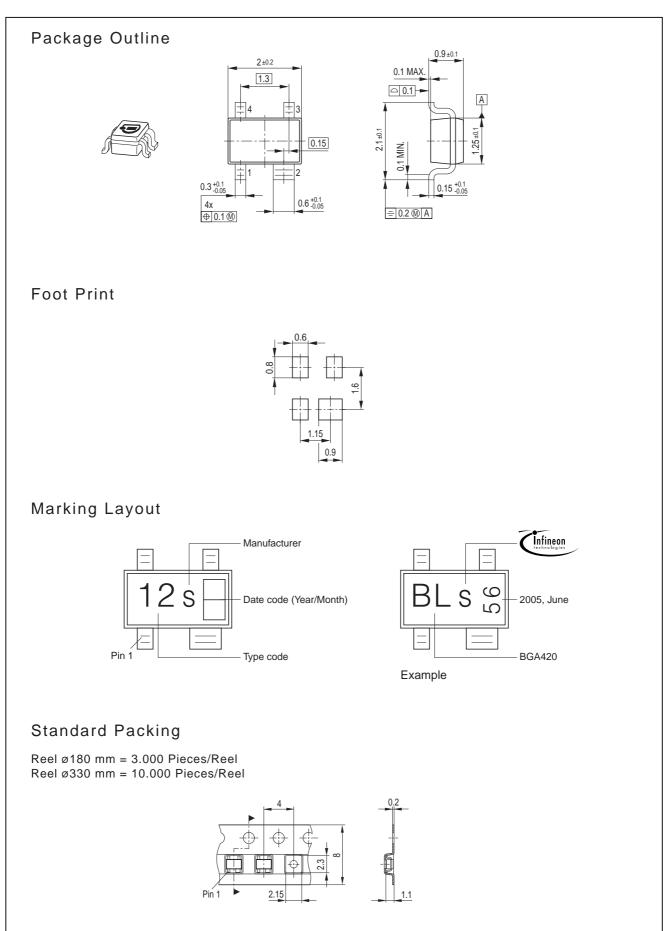


Source impedance for min. noise figure vs. frequency

 $V_{\rm CE} = 3 \text{ V}, I_{\rm C} = 2 \text{ mA} / 5 \text{ mA}$









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